查询HUF75823D3S供应商

FAIRCHILD SEMICONDUCTOR®

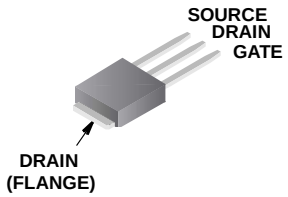
HUF75823D3, HUF75823D3S

Data Sheet **December 2001**

14A, 150V, 0.150 Ohm, N-Channel, UltraFET® Power MOSFET

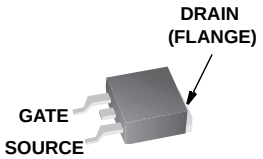
Packaging

JEDEC TO-251AA



HUF75823D3

JEDEC TO-252AA

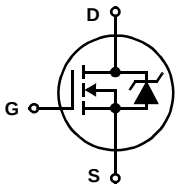


HUF75823D3S

Features

- Ultra Low On-Resistance
  - $r_{DS(ON)}$ = 0.150Ω, V_{GS} = 10V
- Simulation Models
  - Temperature Compensated PSPICE® and SABER™ Electrical Models
  - Spice and SABER Thermal Impedance Models
  - www.fairchildsemi.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve

Symbol



Ordering Information

PART NUMBER	PACKAGE	BRAND
HUF75823D3	TO-251AA	75823D
HUF75823D3S	TO-252AA	75823D

NOTE: When ordering, use the entire part number. Add the suffix T to obtain the variant in tape and reel, e.g., HUF75823D3ST.

Absolute Maximum Ratings T_C = 25°C, Unless Otherwise Specified

		HUF75823D3, HUF75823D3S	UNITS
Drain to Source Voltage (Note 1)	V_{DSS}	150	V
Drain to Gate Voltage (R_{GS} = 20kΩ) (Note 1)	V_{DGR}	150	V
Gate to Source Voltage	V_{GS}	±20	V
Drain Current			
Continuous (T_C= 25°C, V_{GS} = 10V) (Figure 2)	I_D	14	A
Continuous (T_C= 100°C, V_{GS} = 10V) (Figure 2)	I_D	10	A
Pulsed Drain Current	I_{DM}	Figure 4	
Pulsed Avalanche Rating	UIS	Figures 6, 14, 15	
Power Dissipation	P_D	85	W
Derate Above 25°C		0.57	W/°C
Operating and Storage Temperature	T_J, T_{STG}	-55 to 175	°C
Maximum Temperature for Soldering			
Leads at 0.063in (1.6mm) from Case for 10s	T_L	300	°C
Package Body for 10s, See Techbrief TB334	T_{pkg}	260	°C

NOTES:

1. T_J = 25°C to 150°C.

CAUTION: *Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.*

Product reliability information can be found at http://www.fairchildsemi.com/products/discrete/reliability/index.html
For severe environments, see our Automotive HUFA series.
All Fairchild semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

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Electrical Specifications $T_C = 25^oC$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OFF STATE SPECIFICATIONS						
Drain to Source Breakdown Voltage	BV_{DSS}	I_D = 250µA, V_{GS} = 0V (Figure 11)	150	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 140V, V_{GS} = 0V	-	-	1	µA
		V_{DS} = 135V, V_{GS} = 0V, $T_C = 150^oC$	-	-	250	µA
Gate to Source Leakage Current	I_{GSS}	V_{GS} = ±20V	-	-	±100	nA
ON STATE SPECIFICATIONS						
Gate to Source Threshold Voltage	$V_{GS(TH)}$	V_{GS} = V_{DS}, I_D = 250µA (Figure 10)	2	-	4	V
Drain to Source On Resistance	$r_{DS(ON)}$	I_D = 14A, V_{GS} = 10V (Figure 9)	-	0.125	0.150	Ω
THERMAL SPECIFICATIONS						
Thermal Resistance Junction to Case	$R_{\theta JC}$	TO-251 and TO-252	-	-	1.76	$^oC/W$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$		-	-	100	$^oC/W$
SWITCHING SPECIFICATIONS (V_{GS} = 10V)						
Turn-On Time	t_{ON}	V_{DD} = 75V, I_D = 14A V_{GS} = 10V, R_{GS} = 12Ω (Figures 18, 19)	-	-	48	ns
Turn-On Delay Time	$t_{d(ON)}$		-	7.7	-	ns
Rise Time	t_r		-	24	-	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	45	-	ns
Fall Time	t_f		-	26	-	ns
Turn-Off Time	t_{OFF}		-	-	105	ns
GATE CHARGE SPECIFICATIONS						
Total Gate Charge	$Q_{g(TOT)}$	V_{GS} = 0V to 20V; V_{DD} = 75V, I_D = 14A, $I_{g(REF)}$ = 1.0mA (Figures 13, 16, 17)	-	43	54	nC
Gate Charge at 10V	$Q_{g(10)}$	V_{GS} = 0V to 10V	-	23	29	nC
Threshold Gate Charge	$Q_{g(TH)}$	V_{GS} = 0V to 2V	-	1.5	1.9	nC
Gate to Source Gate Charge	Q_{gs}		-	3.4	-	nC
Gate to Drain "Miller" Charge	Q_{gd}		-	8.8	-	nC
CAPACITANCE SPECIFICATIONS						
Input Capacitance	C_{ISS}	V_{DS} = 25V, V_{GS} = 0V, f = 1MHz (Figure 12)	-	800	-	pF
Output Capacitance	C_{OSS}		-	180	-	pF
Reverse Transfer Capacitance	C_{RSS}		-	65	-	pF

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V_{SD}	I_{SD} = 14A	-	-	1.25	V
		I_{SD} = 7A	-	-	1.00	V
Reverse Recovery Time	t_{rr}	I_{SD} = 14A, dI_{SD}/dt = 100A/µs	-	-	150	ns
Reverse Recovered Charge	Q_{RR}	I_{SD} = 14A, dI_{SD}/dt = 100A/µs	-	-	750	nC

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Typical Performance Curves

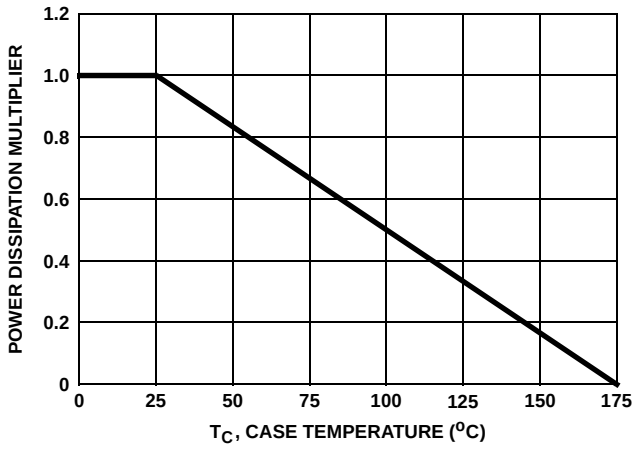


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

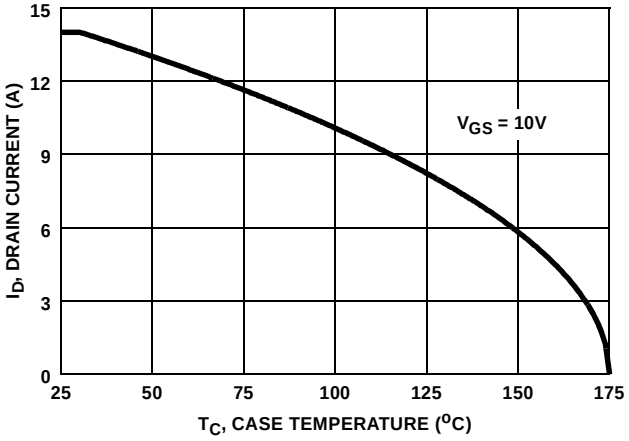


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

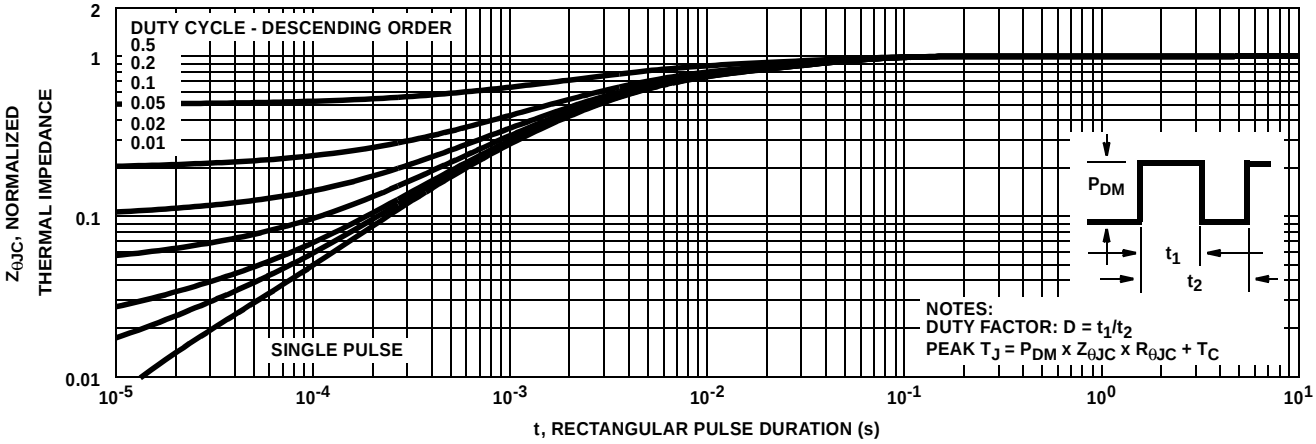


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

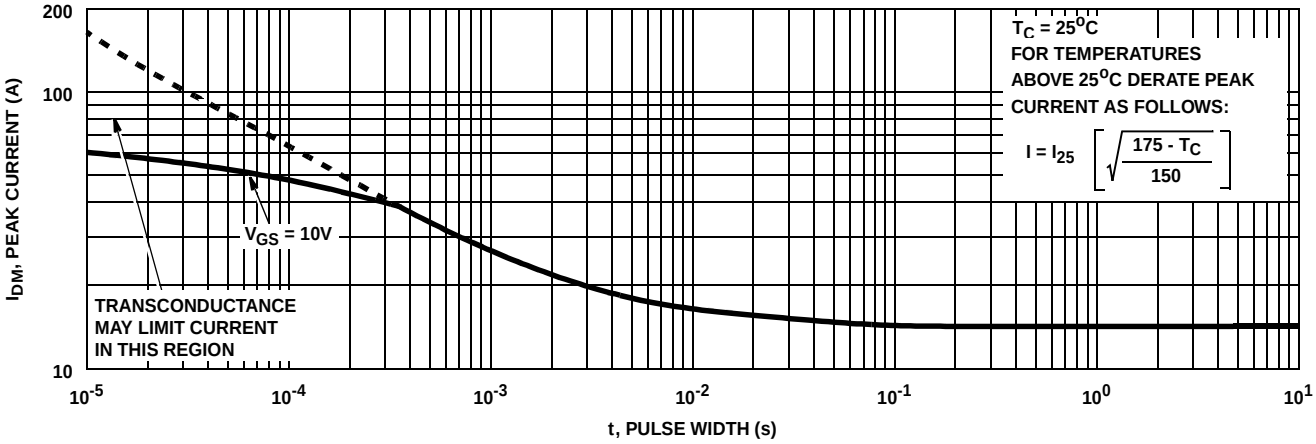


FIGURE 4. PEAK CURRENT CAPABILITY

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Typical Performance Curves (Continued)

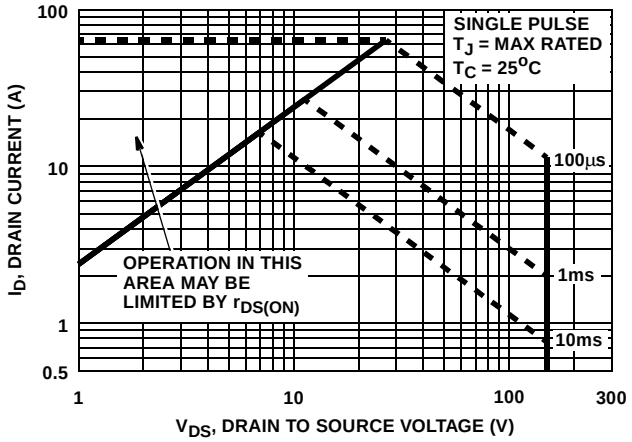
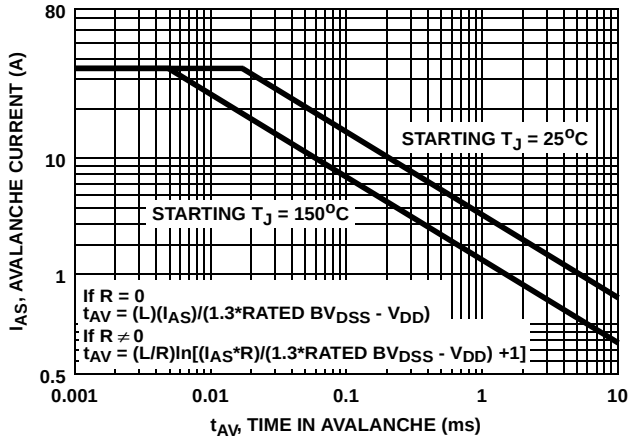


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA



NOTE: Refer to Fairchild Application Notes AN9321 and AN9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

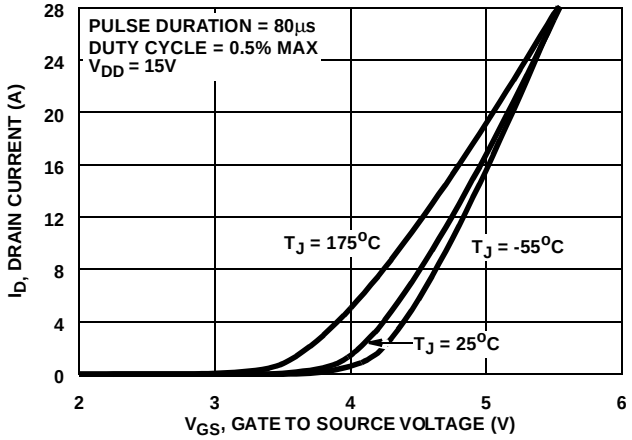


FIGURE 7. TRANSFER CHARACTERISTICS

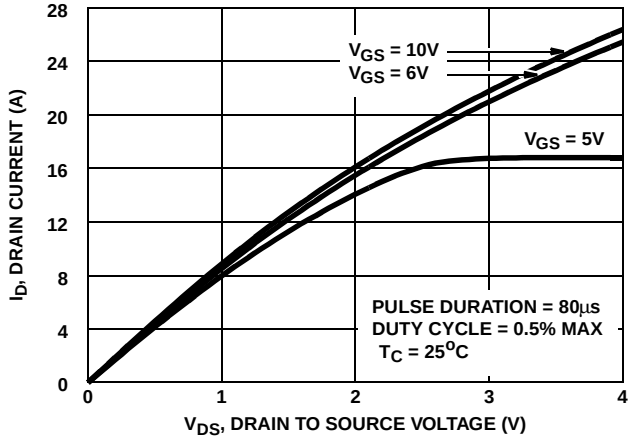


FIGURE 8. SATURATION CHARACTERISTICS

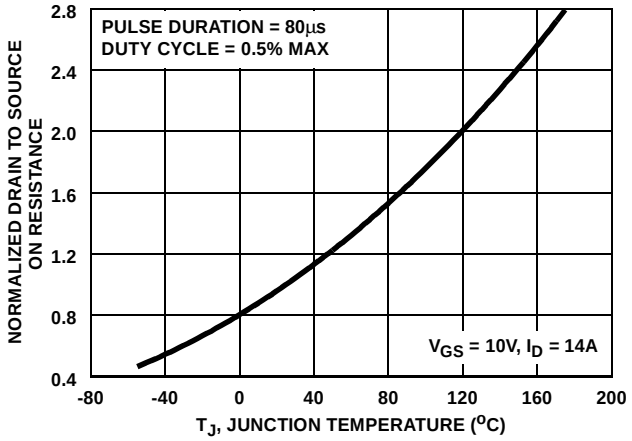


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

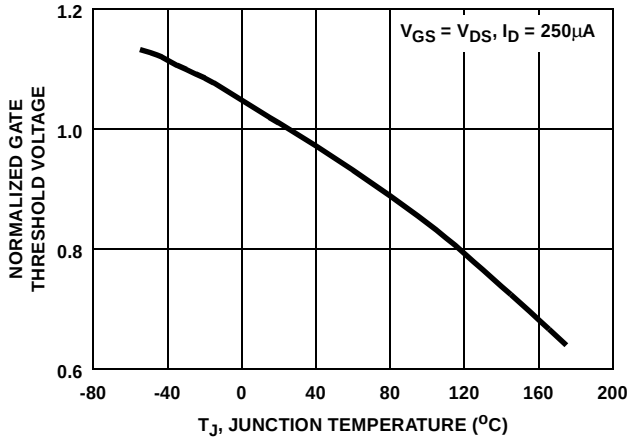


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

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Typical Performance Curves (Continued)

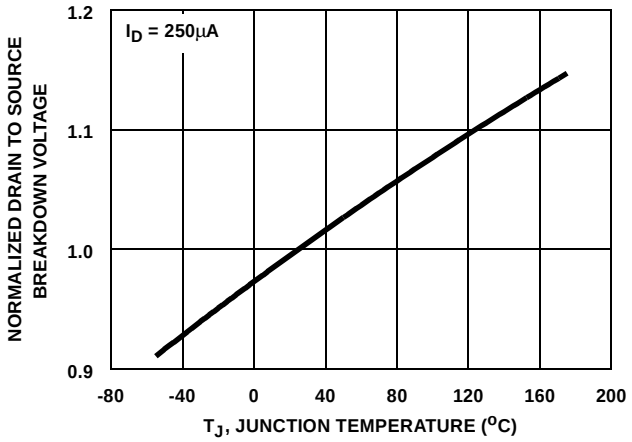


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

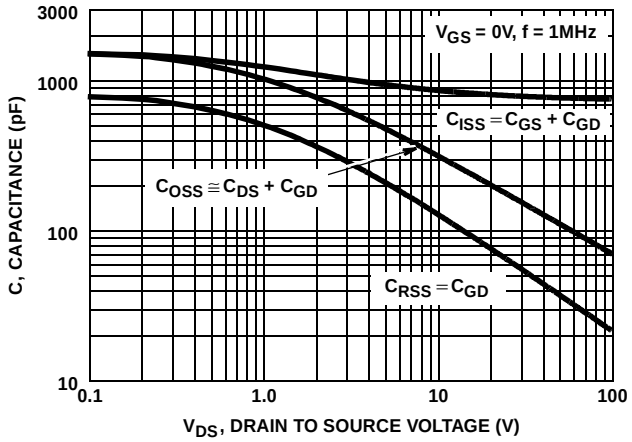
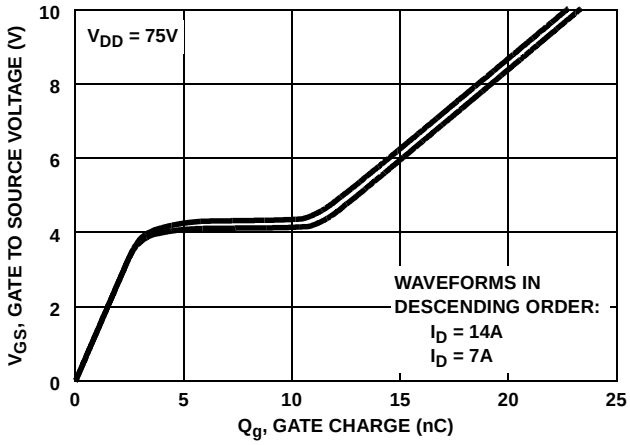


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260.

FIGURE 13. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

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Test Circuits and Waveforms

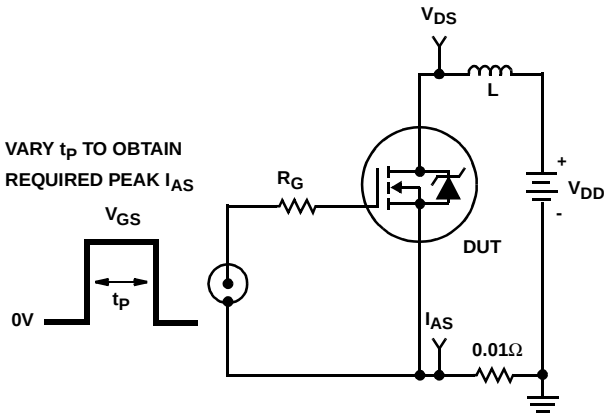


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

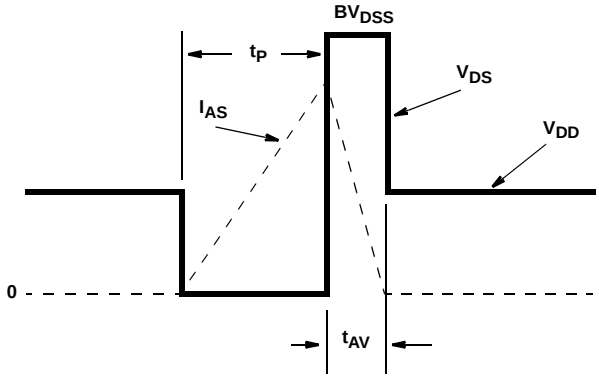


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

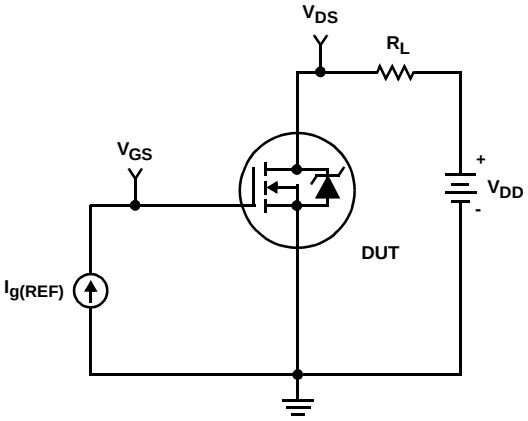


FIGURE 16. GATE CHARGE TEST CIRCUIT

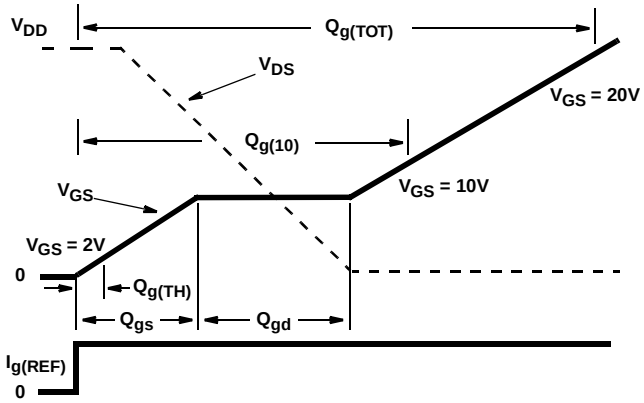


FIGURE 17. GATE CHARGE WAVEFORMS

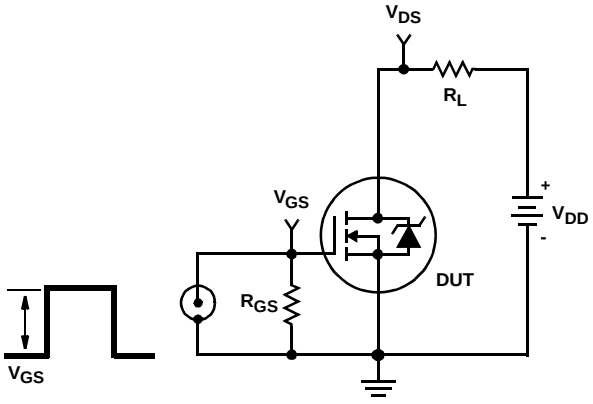


FIGURE 18. SWITCHING TIME TEST CIRCUIT

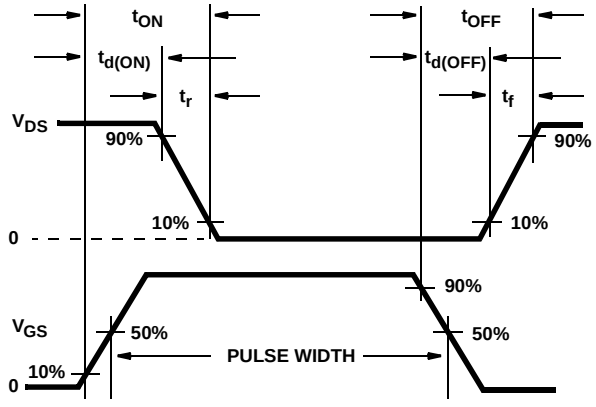


FIGURE 19. SWITCHING TIME WAVEFORM

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PSPICE Electrical Model

.SUBCKT HUF75823 2 1 3 ; rev 18 February 2000

CA 12 8 1.2e-9
CB 15 14 1.3e-9
CIN 6 8 7.4e-10

DBODY 7 5 DBODYMOD
DBREAK 5 11 DBREAKMOD
DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 157.1
EDS 14 8 5 8 1
EGS 13 8 6 8 1
ESG 6 10 6 8 1
EVTHRES 6 21 19 8 1
EVTEMP 20 6 18 22 1

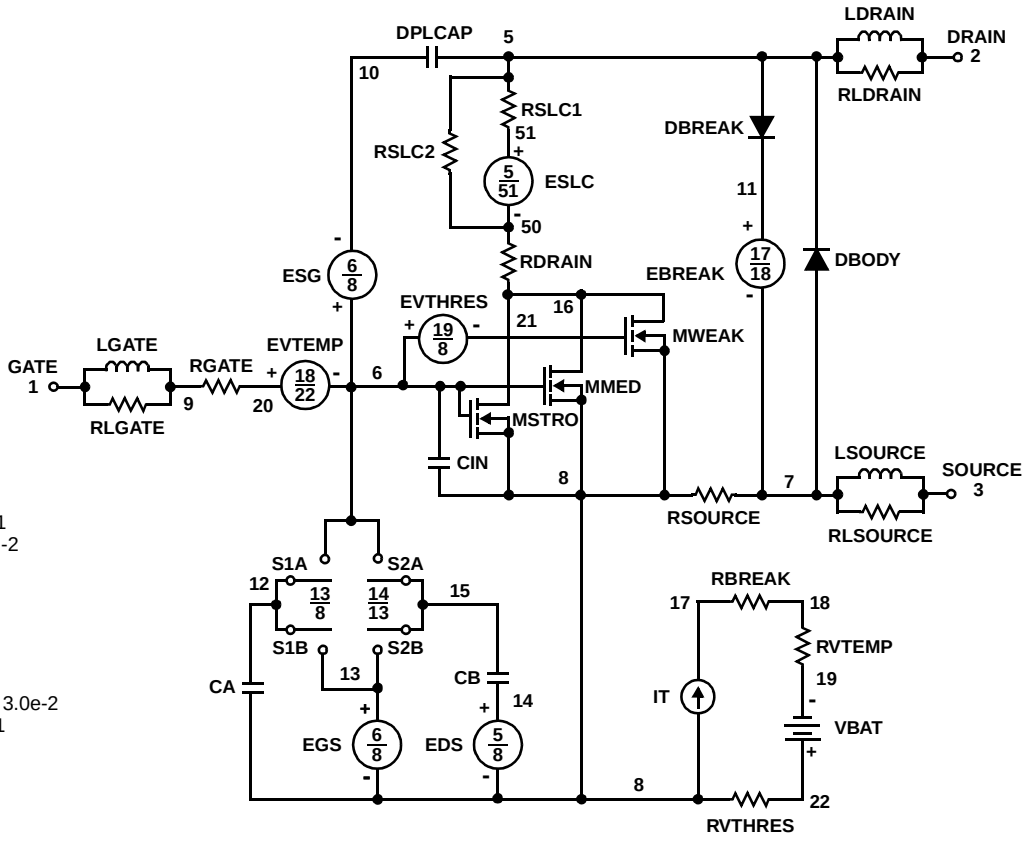
IT 8 17 1

LDRAIN 2 5 1.0e-9
LGATE 1 9 3.11e-9
LSOURCE 3 7 3.72e-9

MMED 16 6 8 8 MMEDMOD
MSTRO 16 6 8 8 MSTROMOD
MWEAK 16 21 8 8 MWEAKMOD

RBREAK 17 18 RBREAKMOD 1
RDRAIN 50 16 RDRAINMOD 7.7e-2
RGATE 9 20 2.13
RLDRAIN 2 5 10
RLGATE 1 9 31.1
RLSOURCE 3 7 37.2
RSLC1 5 51 RSLCMOD 1e-6
RSLC2 5 50 1e3
RSOURCE 8 7 RSOURCEMOD 3.0e-2
RVTHRES 22 8 RVTHRESMOD 1
RVTEMP 18 19 RVTEMPMOD 1

S1A 6 12 13 8 S1AMOD
S1B 13 12 13 8 S1BMOD
S2A 6 15 14 13 S2AMOD
S2B 13 15 14 13 S2BMOD



VBAT 22 19 DC 1

ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*25),3))}

.MODEL DBODYMOD D (IS = 6.5e-13 RS = 1.06e-2 XTI = 5 TRS1 = 2.4e-3 TRS2 = 1.5e-6 CJO = 8.0e-10 TT = 1.1e-7 M = 0.6)
.MODEL DBREAKMOD D (RS = 2. 0TRS1 = 2.0e- 3TRS2 = 1.0e-6)
.MODEL DPLCAPMOD D (CJO = 8.9e-1 0IS = 1e-3 0M = 0.8)
.MODEL MMEDMOD NMOS (VTO = 3.36 KP = 5 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 2.13)
.MODEL MSTROMOD NMOS (VTO = 3.84 KP = 63 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u)
.MODEL MWEAKMOD NMOS (VTO = 2.89 KP = 0.08 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 21.3)
.MODEL RBREAKMOD RES (TC1 = 1.08e- 3TC2 = -6.0e-7)
.MODEL RDRAINMOD RES (TC1 = 1.1e-2 TC2 = 2.7e-5)
.MODEL RSLCMOD RES (TC1 = 3.5e-3 TC2 = 2.0e-6)
.MODEL RSOURCEMOD RES (TC1 = 1e-3 TC2 = 1e-6)
.MODEL RVTHRESMOD RES (TC1 = -2.8e-3 TC2 = -9.0e-6)
.MODEL RVTEMPMOD RES (TC1 = -2.1e- 3TC2 = -9.0e-7)

.MODEL S1AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -5.8 VOFF= -2.4)
.MODEL S1BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -2.4 VOFF= -5.8)
.MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -1.8 VOFF= 0.5)
.MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0.5 VOFF= -1.8)

.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

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SABER Electrical Model

REV 18 February 2000

```
template huf75823 n2,n1,n3
electrical n2,n1,n3
{
var i iscl
dp..model dbodymod =  (is = 6.5e-13, rs = 1.06e-2, xti = 5, trs1 = 2.4e-3, trs2 = 1.5e-6, cjo = 8.0e-10, tt = 1.1e-7, m = 0.6)
dp..model dbreakmod = (rs = 2.0, trs1 = 2.0e-3, trs2 = 1.0e-6)
dp..model dplcapmod =  (cjo = 8.9e-10, is = 10e-30, m = 0.8)
m..model mmedmod = (type=_n, vto = 3.36, kp = 5, is = 1e-30, tox = 1)
m..model mstrongmod = (type=_n, vto = 3.84, kp = 63, is = 1e-30, tox = 1)
m..model mweakmod = (type=_n, vto = 2.89, kp = 0.08, is = 1e-30, tox = 1)
sw_vcsp..model s1amod =  (ron = 1e-5, roff = 0.1, von = -5.8, voff = -2.4)
sw_vcsp..model s1bmod =  (ron = 1e-5, roff = 0.1, von = -2.4, voff = -5.8)
sw_vcsp..model s2amod =  (ron = 1e-5, roff = 0.1, von = -1.8, voff = 0.5)
sw_vcsp..model s2bmod =  (ron = 1e-5, roff = 0.1, von = 0.5, voff = -1.8)

c.ca n12 n8 = 1.2e-9
c.cb n15 n14 = 1.3e-9
c.cin n6 n8 = 7.4e-10

dp.dbody n7 n5 = model=dbodymod
dp.dbreak n5 n11 = model=dbreakmod
dp.dplcap n10 n5 = model=dplcapmod

i.it n8 n17 = 1

l.ldrain n2 n5 = 1.0e-9
l.lgate n1 n9 = 3.11e-9
l.lsource n3 n7 = 3.72e-9

m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u
m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u
m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u

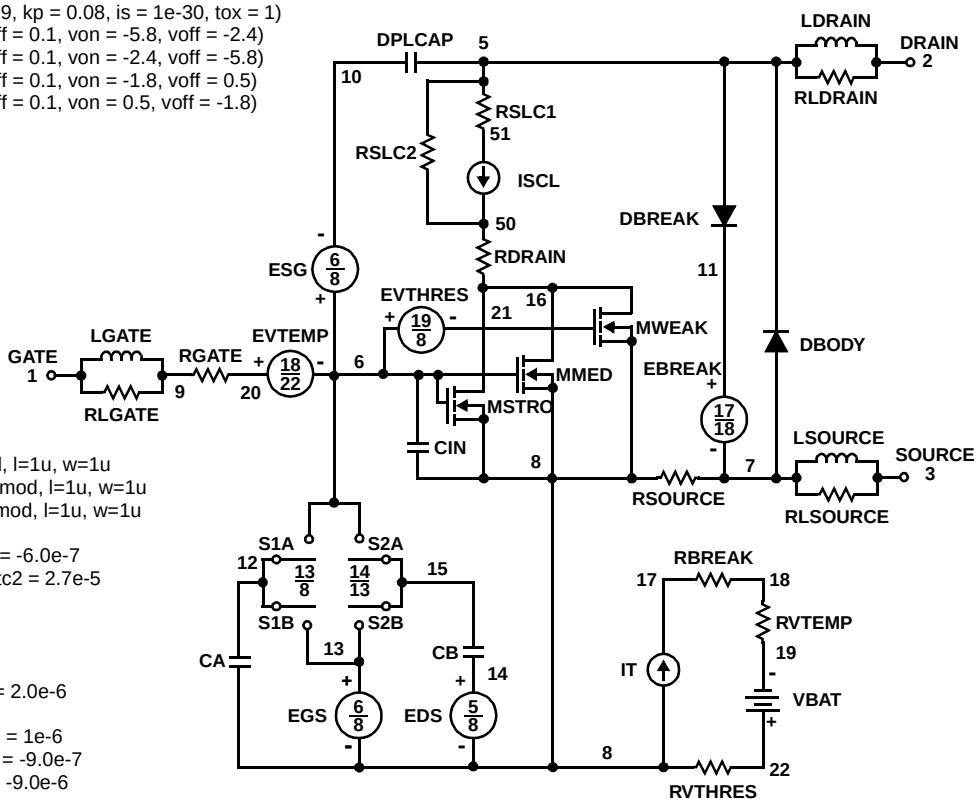
res.rbreak n17 n18  = 1, tc1 = 1.08e-3, tc2 = -6.0e-7
res.rdrain n50 n16  = 7.7e-2, tc1 = 1.1e-2, tc2 = 2.7e-5
res.rgate n9 n20 = 2.13
res.rldrain n2 n5 = 10
res.rlgate n1 n9 = 31.1
res.rlsource n3 n7 = 37.2
res.rslc1 n5 n51  = 1e-6, tc1 = 3.5e-3, tc2 = 2.0e-6
res.rslc2 n5 n50 = 1e3
res.rsource n8 n7  = 3.0e-2, tc1 = 1e-3, tc2 = 1e-6
res.rvtemp n18 n19  = 1, tc1 = -2.1e-3, tc2 = -9.0e-7
res.rvthres n22 n8  = 1, tc1 = -2.8e-3, tc2 = -9.0e-6

spe.ebreak n11 n7 n17 n18 = 157.1
spe.eds n14 n8 n5 n8 = 1
spe.egs n13 n8 n6 n8 = 1
spe.esg n6 n10 n6 n8 = 1
spe.evtemp n20 n6 n18 n22 = 1
spe.evthres n6 n21 n19 n8 = 1

sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod
sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod
sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod
sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod

v.vbat n22 n19 = dc=1

equations {
i (n51->n50) +=iscl
iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/25))** 3))
}
}
```



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SPICE Thermal Model

REV 25 October 1999

HUF75823D

CTHERM1 th 6 1.40e-3
CTHERM2 6 5 5.55e-3
CTHERM3 5 4 5.65e-3
CTHERM4 4 3 6.10e-3
CTHERM5 3 2 9.80e-3
CTHERM6 2 tl 7.70e-2

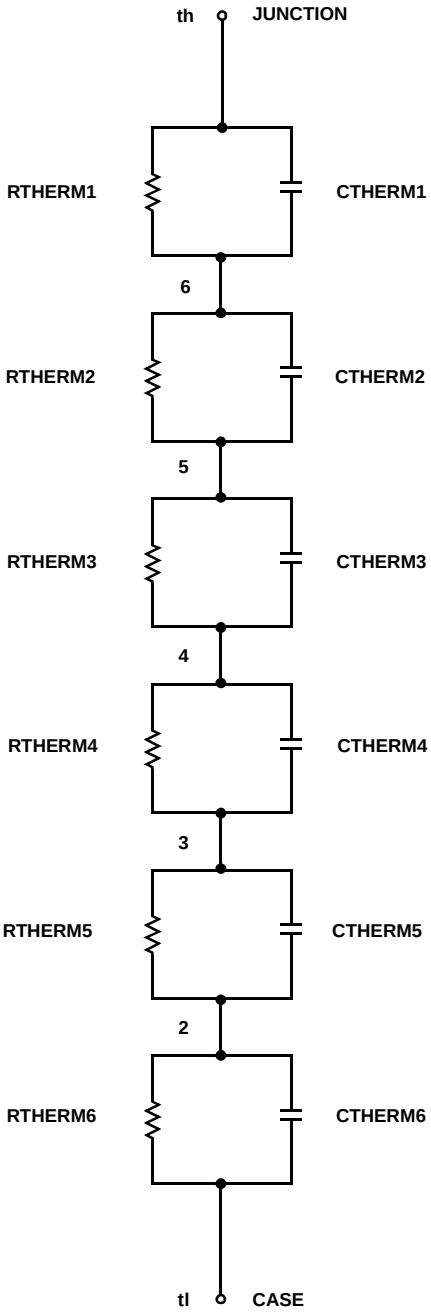
RTHERM1 th 6 1.10e-2
RTHERM2 6 5 5.80e-2
RTHERM3 5 4 1.35e-1
RTHERM4 4 3 3.60e-1
RTHERM5 3 2 4.13e-1
RTHERM6 2 tl 4.30e-1

SABER Thermal Model

SABER thermal model HUF75823D

template thermal_model th tl
thermal_c th, tl
{
ctherm.ctherm1 th 6 = 1.40e-3
ctherm.ctherm2 6 5 = 5.55e-3
ctherm.ctherm3 5 4 = 5.65e-3
ctherm.ctherm4 4 3 = 6.10e-3
ctherm.ctherm5 3 2 = 9.80e-3
ctherm.ctherm6 2 tl = 7.70e-2

rtherm.rtherm1 th 6 = 1.10e-2
rtherm.rtherm2 6 5 = 5.80e-2
rtherm.rtherm3 5 4 = 1.35e-1
rtherm.rtherm4 4 3 = 3.60e-1
rtherm.rtherm5 3 2 = 4.13e-1
rtherm.rtherm6 2 tl = 4.30e-1
}



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